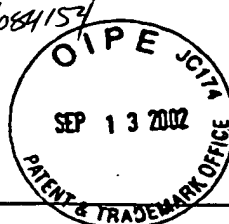


	ATTY. DOCKET NO. 2000P03099WOUS		SERIAL NO. 10/084153
			
	APPLICANT Siemens Aktiengesellschaft		
FILING DATE		GROUP	

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		PATENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>MS</i>	AA	4,595,340	17.Jun. 1986	Klassen David			
	AB	5,407,326	18. April 1995	Lerdellier, Alain			
	AC	3,695,778	03.Oct. 1972	Taylor, John			

## FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION

		DOCUMENT NO.	PUBL DATE	COUNTRY OR PATENT OFFICE	CLASS	SUB CLASS	TRANSLATION YES NO
<i>MS</i>	AD	EP 0,924,381	23. Jun. 1999	EPO			

## OTHER DOCUMENTS (Including Author, Title, Date, Relevant Pages, Place of Publication)

		<b>RECEIVED</b> SEP 17 2002 <b>GROUP 3600</b>
EXAMINER	<i>Paul Jones</i>	DATE CONSIDERED 3/11/06
EXAMINER: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.		

Best Available Copy

Form PTO-1449  <b>INFORMATION DISCLOSURE CITATION IN AN APPLICATION</b>  (Use several sheets if necessary)		ATTY DOCKET NO. <b>32860-000280/US</b>		APPLICATION NO. <b>10/084,154</b>	
		APPLICANT <b>Christiane FOERTSCH et al.</b>		CONF. NO. <b>4901</b>	
		FILING DATE <b>February 28, 2002</b>		GROUP <b>UNKNOWN</b>	

U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE

RECEIVED  
JUN 05 2002  
Technology Center 2700

FOREIGN PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION	
						YES	NO
Mj	DE 196 14 789 C1	9/25/97	GERMANY			PART. ABST.	
	DE 199 18 810 A1	11/2/00	GERMANY			PART. ABST.	
	DE 196 30 415 A1	1/15/98	GERMANY			PART. ABST.	
	<del>DE 299 14 463 U1</del>	<del>11/2/2000</del>	<del>GERMANY</del>				X

RECEIVED  
JUL 15 2002  
GROUP 3600

OTHER DOCUMENTS	
EXAMINER INITIAL	<small>(Include Name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.) date, page(s), volume-issue number(s), publisher, city and/or country where published.)</small>  <div style="margin-top: 10px;"> <span style="font-size: 1.5em; margin-right: 10px;">Mj</span> WOLFGANG KÄFER ET AL.: "Konfigurierungskonzepte für DB-basierte technisch Entwurfsanwendungen", <u>Informatik Forschung und Entwicklung</u>, pp. 1-17, 1998.           </div> <div style="margin-top: 10px;"> <span style="font-size: 1.5em; margin-right: 10px;">Mj</span> PETER VAN DEN HAMER ET AL.: "Managing Design Data: The Five Dimensions of CAD Frameworks, Configuration Management, and Product Data Management", <u>Proceedings of the IEEE</u>, Vol. 84, No. 1, pp. 42-56, January 1996.           </div> <div style="margin-top: 10px;"> REINHARD SCHRIEBER: "Planungsmethoden und Planungswerkzeuge für die Prozeßleitetchnik", ATP, pp. 41-54, June 1994.         </div>

EXAMINER 	DATE CONSIDERED 3/11/06
--------------	----------------------------

EXAMINER: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

**Best Available Copy**

no  
translation